

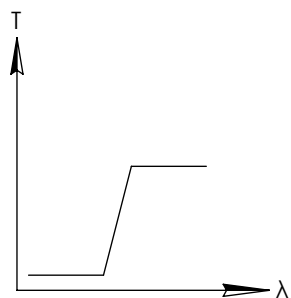
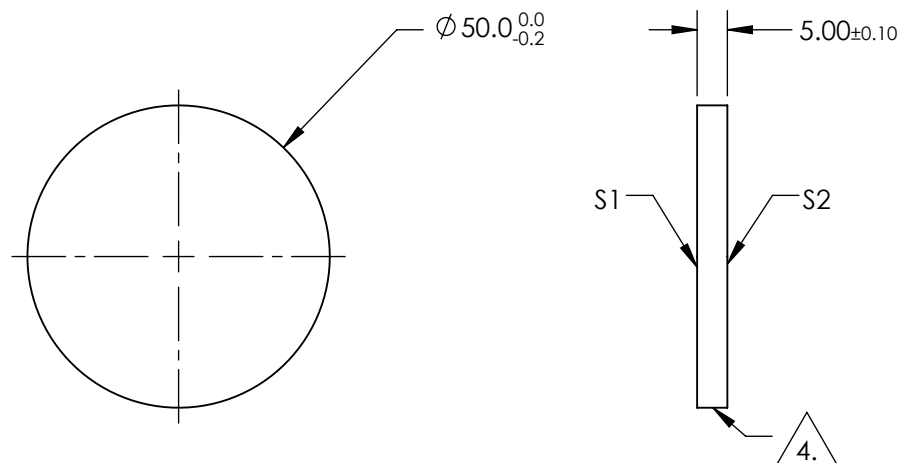
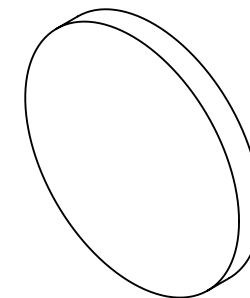
NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
 S1: HARD DIELECTRIC SPUTTERED
 T(avg): $\geq 91\%$ FROM 408 - 1650nm @ 0° AOI
 T(avg): $\leq 0.01\%$ FROM 200 - 390nm @ 0° AOI
 T(abs): =50% FOR 400±4nm @ 0° AOI
 S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS
 APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: $\leq \lambda/4$ @ 633nm
7. ROHS COMPLIANT

**FOR INFORMATION ONLY:
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 PARTS TO THIS DRAWING**



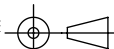
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

EO® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø50mm, 400nm, HIGH PERFORMANCE
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

84754

SHEET
 1 OF 1

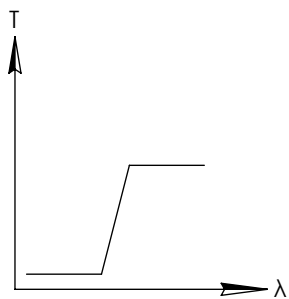
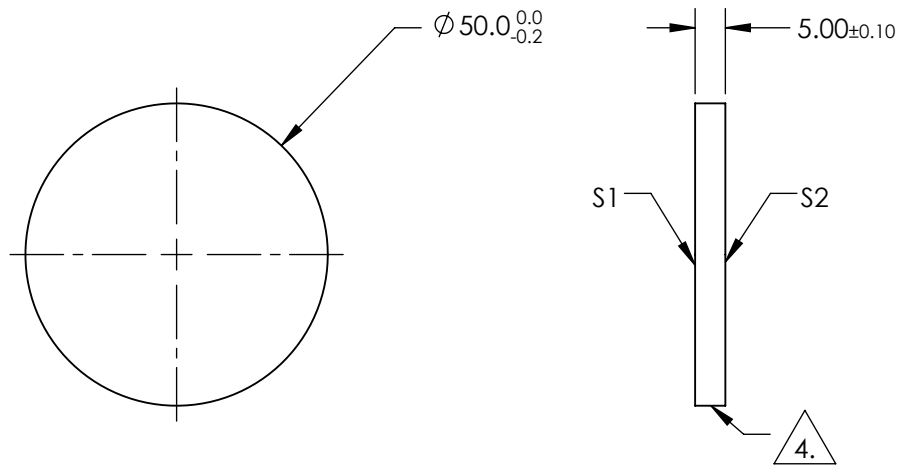
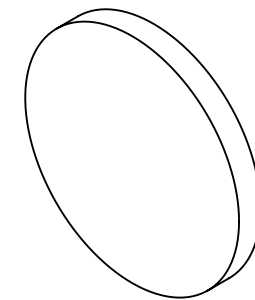
NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
 S1: HARD DIELECTRIC SPUTTERED
 T(avg): $\geq 91\%$ FROM 458 - 1650nm @ 0° AOI
 T(avg): $\leq 0.01\%$ FROM 200 - 440nm @ 0° AOI
 T(abs): =50% FOR 450±4.5nm @ 0° AOI
 S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: $\leq \lambda/4$ @ 633nm
7. ROHS COMPLIANT

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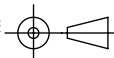


LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

THIRD ANGLE PROJECTION



ALL DIMS IN

mm

EO® Edmund Optics®

TITLE

Ø50mm, 450nm, HIGH PERFORMANCE
LONGPASS FILTER

DWG NO

84755

SHEET
1 OF 1

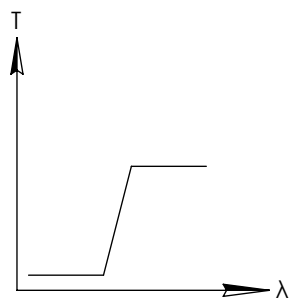
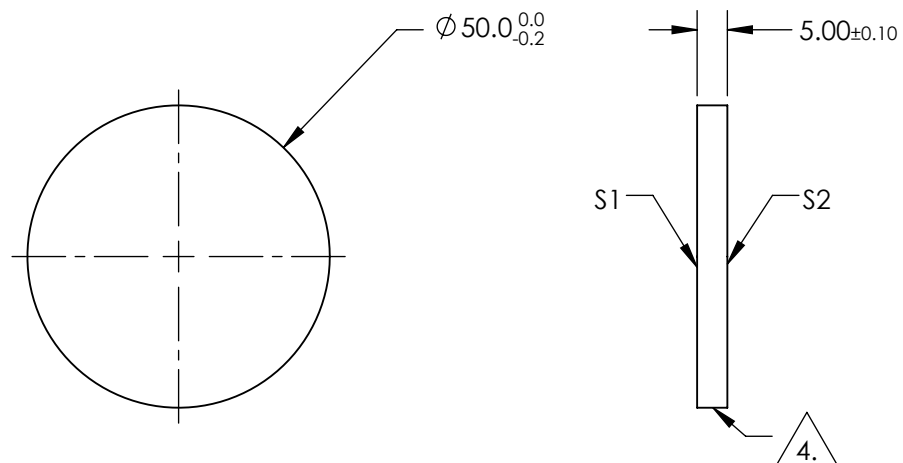
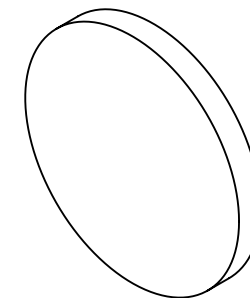
NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
 S1: HARD DIELECTRIC SPUTTERED
 T(avg): $\geq 91\%$ FROM 508 - 1650nm @ 0° AOI
 T(avg): $\leq 0.01\%$ FROM 200 - 490nm @ 0° AOI
 T(abs): =50% FOR 500±5nm @ 0° AOI
 S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: $\leq \lambda/4$ @ 633nm
7. ROHS COMPLIANT

**FOR INFORMATION ONLY:
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PARTS TO THIS DRAWING**



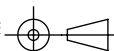
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

EO® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø50mm, 500nm, HIGH PERFORMANCE
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

84756

SHEET
1 OF 1

NOTES:

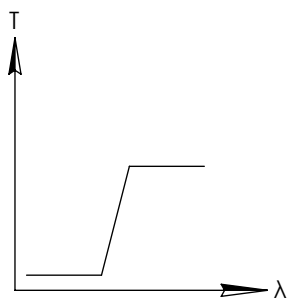
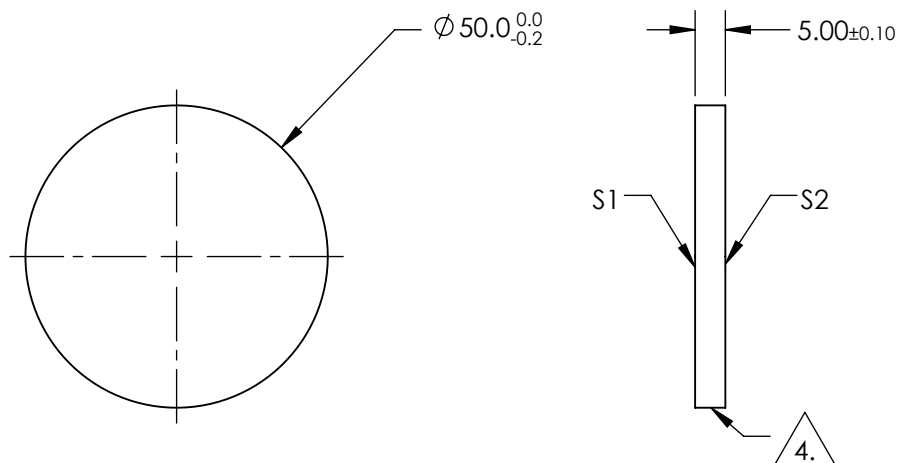
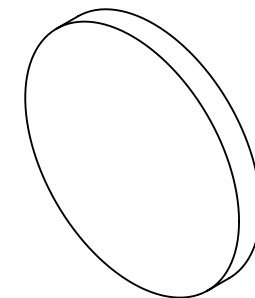
**FOR INFORMATION ONLY:
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PARTS TO THIS DRAWING**

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
S1: HARD DIELECTRIC SPUTTERED
T(avg): ≥91% FROM 560 - 1650nm @ 0° AOI
T(avg): ≤0.01% FROM 200 - 539nm @ 0° AOI
T(abs): =50% FOR 550±5.5nm @ 0° AOI

S2:SINGLE LAYER MgF2

△ FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS
APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT



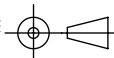
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

EO® Edmund Optics®

THIRD ANGLE
PROJECTION



TITLE

Ø50mm, 550nm, HIGH PERFORMANCE
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

84757

SHEET
1 OF 1

NOTES:

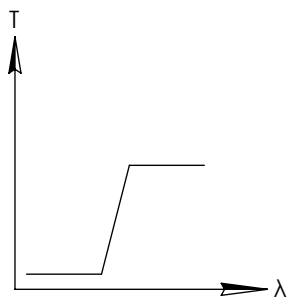
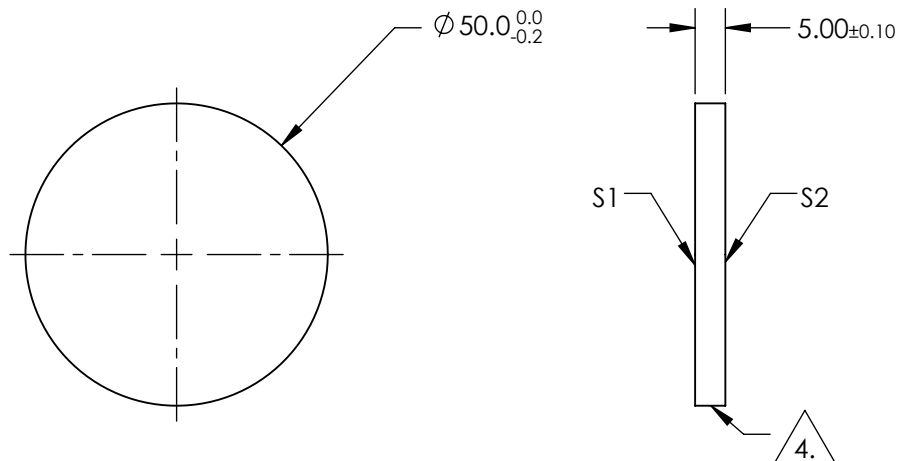
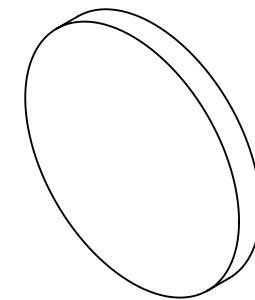
**FOR INFORMATION ONLY:
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PARTS TO THIS DRAWING**

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
 S1: HARD DIELECTRIC SPUTTERED
 T(avg): $\geq 91\%$ FROM 610 - 1650nm @ 0° AOI
 T(avg): $\leq 0.01\%$ FROM 200 - 588nm @ 0° AOI
 T(abs): =50% FOR 600±6nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS
 APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: $\leq \lambda/4$ @ 633nm
7. ROHS COMPLIANT



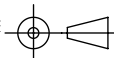
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

EO® Edmund Optics®

THIRD ANGLE
 PROJECTION



TITLE

Ø50mm, 600nm, HIGH PERFORMANCE
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

84758

SHEET
 1 OF 1

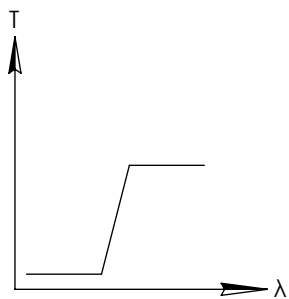
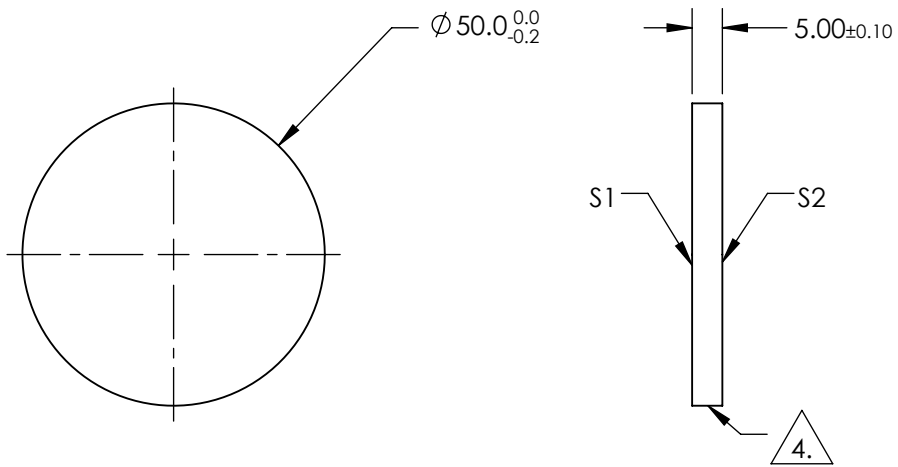
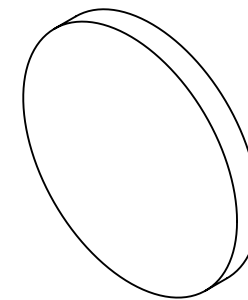
NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
 S1: HARD DIELECTRIC SPUTTERED
 T(avg): $\geq 91\%$ FROM 660 - 1650nm @ 0° AOI
 T(avg): $\leq 0.01\%$ FROM 200 - 637nm @ 0° AOI
 T(abs): =50% FOR 650±6.5nm @ 0° AOI
 S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: $\leq \lambda/4$ @ 633nm
7. ROHS COMPLIANT

**FOR INFORMATION ONLY:
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PARTS TO THIS DRAWING**



LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

EO® Edmund Optics®

THIRD ANGLE PROJECTION

ALL DIMS IN mm

TITLE	Ø50mm, 650nm, HIGH PERFORMANCE LONGPASS FILTER		
DWG NO	84759	SHEET	1 OF 1

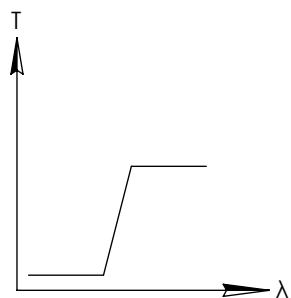
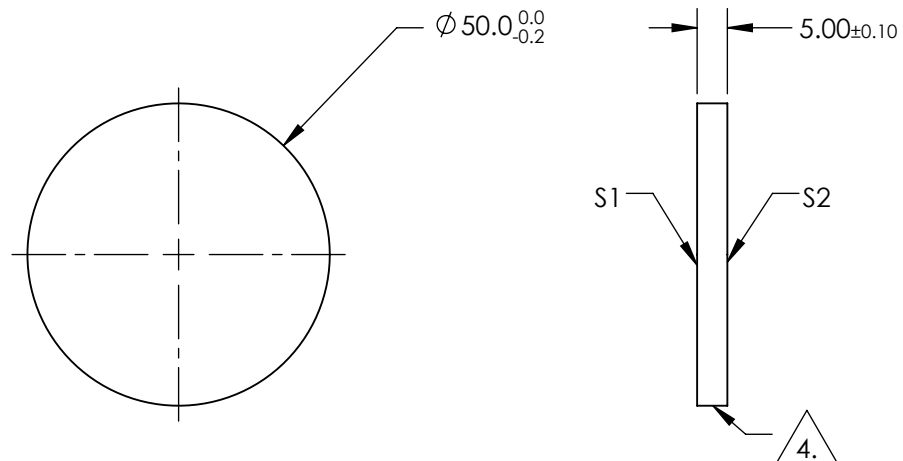
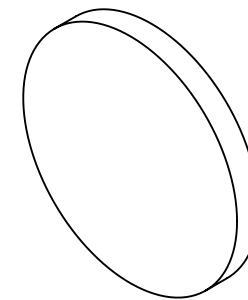
NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
 S1: HARD DIELECTRIC SPUTTERED
 T(avg): $\geq 91\%$ FROM 710 - 1650nm @ 0° AOI
 T(avg): $\leq 0.01\%$ FROM 200 - 686nm @ 0° AOI
 T(abs): =50% FOR 700±7nm @ 0° AOI
 S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS
 APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: $\leq \lambda/4$ @ 633nm
7. ROHS COMPLIANT

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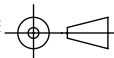
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

EO® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø50mm, 700nm, HIGH PERFORMANCE
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

84760

SHEET
 1 OF 1